



Patent  
Attorney Docket No. 027260-664

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of

Maeno, Hideshi

Application No.: 10/725,028

Filing Date: December 2, 2003

Title: Semiconductor Integrated Circuit with Test Circuit

Group Art Unit: 2133

Examiner: Unassigned

Confirmation No.: 4717

**REQUEST FOR CORRECTED OFFICIAL FILING RECEIPT**

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Sir:

Enclosed is a copy of the Official Filing Receipt marked in red to show correction(s) that is needed. The correction(s) is as follows:

Assignment for Published Patent Application:

Please change from "RENESA'S TECHNOLOGY CORP." to "R NESAS TECHNOLOGY CORP."

Issuance of a corrected Official Filing Receipt is respectfully requested.

Respectfully submitted,

BURNS, DOANE, SWECKER & MATHIS, L.L.P.

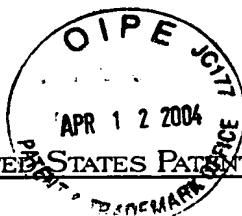
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Date: April 12, 2004

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## UNITED STATES PATENT AND TRADEMARK OFFICE

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10/725,028	12/02/2003	2133	770	027260-664	22	18	1

CONFIRMATION NO. 4717

## FILING RECEIPT



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21839  
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Receipt is acknowledged of this regular Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Filing Receipt Corrections, facsimile number 703-746-9195. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the USPTO processes the reply to the Notice, the USPTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).

## Applicant(s)

Hideshi Maeno, Tokyo, JAPAN;

## Assignment For Published Patent Application

~~RENESAS TECHNOLOGY CORP.;~~  
**RENESAS**

## Domestic Priority data as claimed by applicant

This application is a CIP of 10/611,172 07/02/2003

## Foreign Applications

JAPAN 2002-364099 12/16/2002

JAPAN 2003-353924 10/14/2003

If Required, Foreign Filing License Granted: 01/13/2004

Projected Publication Date: 06/17/2004

Non-Publication Request: No

Early Publication Request: No

## Title

Semiconductor integrated circuit with test circuit

JAN 20 04

